

100302 Low Power Quint 2-Input OR/NOR Gate

General Description

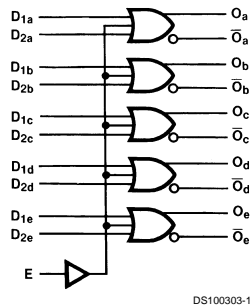
The 100302 is a monolithic quint 2-input OR/NOR gate with common enable. All inputs have 50 kΩ pull-down resistors and all outputs are buffered.

- 2000V ESD protection
- Pin/function compatible with 100102
- Voltage compensated operating range = -4.2V to -5.7V
- Standard Microcircuit Drawing (SMD) 5962-9152802

Features

- 43% power reduction of the 100102

Logic Symbol



Pin Names	Description
$D_{na}-D_{ne}$	Data Inputs
E	Enable Input
O_a-O_e	Data Outputs
$\bar{O}_a-\bar{O}_e$	Complementary Data Outputs

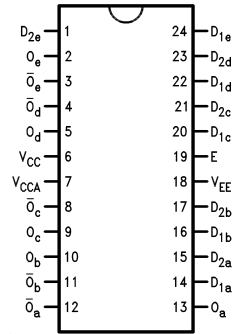
Truth Table

D_{1x}	D_{2x}	E	O_x	\bar{O}_x
L	L	L	L	H
L	L	H	H	L
L	H	L	H	L
L	H	H	H	L
H	L	L	H	L
H	L	H	H	L
H	H	L	H	L
H	H	H	H	L

H = HIGH Voltage Level
L = LOW Voltage Level

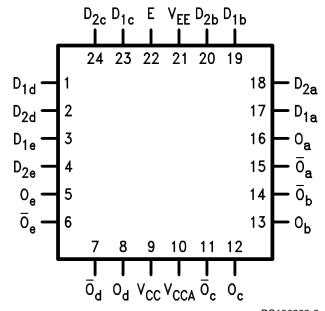
Connection Diagrams

24-Pin DIP



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24-Pin Quad Cerpak



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Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Above which the useful life may be impaired	
Storage Temperature (T_{STG})	-65°C to +150°C
Maximum Junction Temperature (T_J)	
Ceramic	+175°C
V_{EE} Pin Potential to Ground Pin	-7.0V to +0.5V
Input Voltage (DC)	V_{EE} to +0.5V
Output Current (DC Output HIGH)	-50 mA

ESD (Note 2)

≥2000V

Recommended Operating Conditions

Case Temperature (T_C)	
Military	-55°C to +125°C
Supply Voltage (V_{EE})	-5.7V to -4.2V

Note 1: Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: ESD testing conforms to MIL-STD-883, Method 3015.

Military Version DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -55°C$ to $+125°C$ (Note 5)

Symbol	Parameter	Min	Max	Units	T_C	Conditions	Notes	
V_{OH}	Output HIGH Voltage	-1025	-870	mV	0°C to +125°C	$V_{IN} = V_{IH(Max)}$ or $V_{IL} (Min)$	Loading with 50Ω to -2.0V	(Notes 3, 4, 5)
		-1085	-870	mV	-55°C			
V_{OL}	Output LOW Voltage	-1830	-1620	mV	0°C to +125°C	$V_{IN} = V_{IH(Max)}$ or $V_{IL} (Min)$	Loading with 50Ω to -2.0V	(Notes 3, 4, 5)
		-1830	-1555	mV	-55°C			
V_{OHC}	Output HIGH Voltage	-1035		mV	0°C to +125°C	$V_{IN} = V_{IH(Max)}$ or $V_{IL} (Min)$	Loading with 50Ω to -2.0V	(Notes 3, 4, 5)
V_{OLC}	Output LOW Voltage		-1610	mV	0°C to +125°C			
			-1555	mV	-55°C			
V_{IH}	Input HIGH Voltage	-1165	-870	mV	-55°C to +125°C	Guaranteed HIGH Signal for All Inputs	(Notes 3, 4, 5, 6)	
V_{IL}	Input LOW Voltage	-1830	-1475	mV	-55°C to +125°C	Guaranteed LOW Signal for All Inputs	(Notes 3, 4, 5, 6)	
I_{IL}	Input LOW Current	0.50		μA	-55°C to +125°C	$V_{EE} = -4.2V$ $V_{IN} = V_{IH} (Max)$	(Notes 3, 4, 5)	
I_{IH}	Input HIGH Current		240	μA	0°C to +125°C	$V_{EE} = -5.7V$ $V_{IN} = V_{IL}(Min)$	(Notes 3, 4, 5)	
			340	μA	-55°C			
I_{EE}	Power Supply Current	-48	-17	mA	-55°C to +125°C	Inputs Open	(Notes 3, 4, 5, 6)	

Note 3: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals -55°C), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 4: Screen tested 100% on each device at -55°C, +25°C, and +125°C, Subgroups 1, 2, 3, 7, and 8.

Note 5: Sample tested (Method 5005, Table I) on each manufactured lot at -55°C, +25°C, and +125°C, Subgroups A1, 2, 3, 7, and 8.

Note 6: Guaranteed by applying specified input condition and testing V_{OH}/V_{OL} .

AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55°C$		$T_C = +25°C$		$T_C = +125°C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
t_{PLH}	Propagation Delay	0.30	1.80	0.40	1.50	0.40	1.70	ns	Figures 1, 2	(Notes 7, 8, 9, 10, 11)
t_{PHL}	Data to Output									
t_{PLH}	Propagation Delay	0.60	2.60	0.80	2.30	0.80	2.80	ns	Figures 1, 2	(Note 10)
t_{PHL}	Enable to Output									
t_{TLH}	Transition Time	0.30	1.20	0.30	1.20	0.30	1.20	ns	Figures 1, 2	(Note 10)
t_{THL}	20% to 80%, 80% to 20%									

Note 7: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals -55°C), then testing immediately after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

AC Electrical Characteristics (Continued)

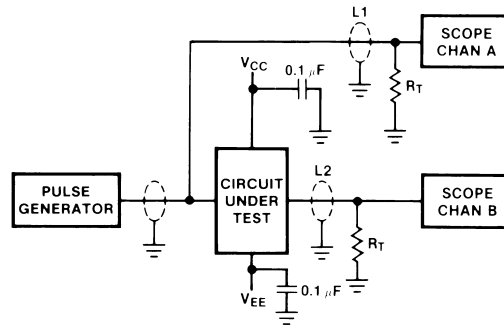
Note 8: Screen tested 100% on each device at +25°C temperature only, Subgroup A9.

Note 9: Sample tested (Method 5005, Table I) on each manufactured lot at +25°C, Subgroup A9, and at +125°C and -55°C temperatures, Subgroups A10 and A11.

Note 10: Not tested at +25°C, +125°C, and -55°C temperature (design characterization data).

Note 11: The propagation delay specified is for single output switching. Delays may vary up to 100 ps with multiple outputs switching.

Test Circuitry



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Notes:

$V_{CC}, V_{CCA} = +2V, V_{EE} = -2.5V$

L1 and L2 = equal length 50Ω impedance lines

$R_T = 50\Omega$ terminator internal to scope

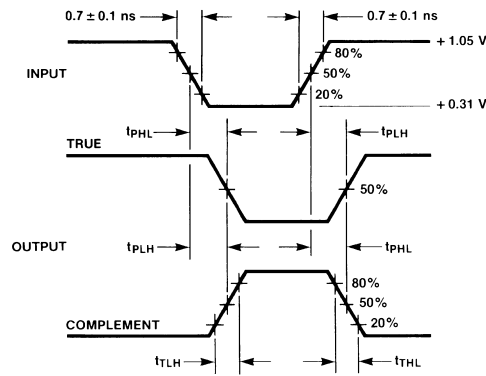
Decoupling 0.1 μF from GND to V_{CC} and V_{EE}

All unused outputs are loaded with 50Ω to GND

C_L = Fixture and stray capacitance ≤ 3 pF

FIGURE 1. AC Test Circuit

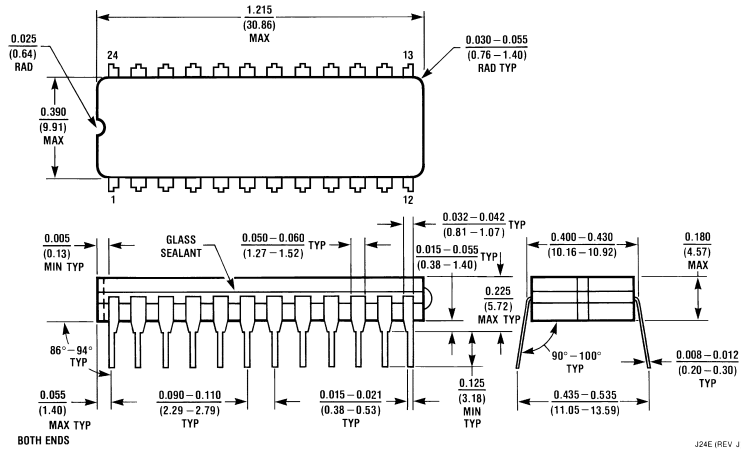
Switching Waveforms



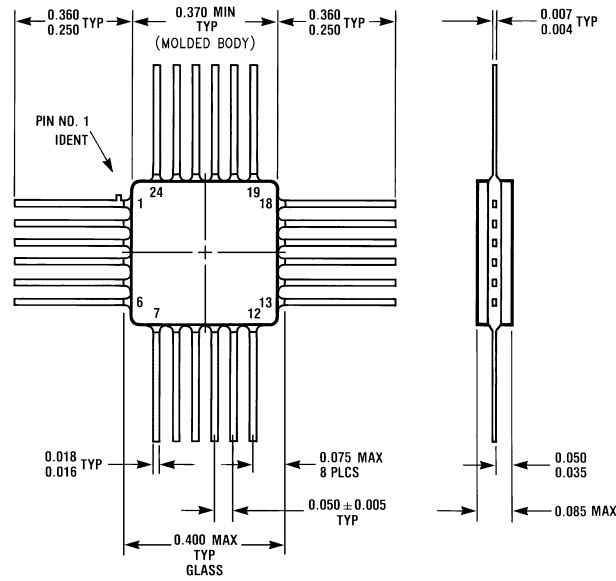
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FIGURE 2. Propagation Delay and Transition Times

Physical Dimensions inches (millimeters) unless otherwise noted



24-Lead Ceramic Dual-In-Line Package (0.400" Wide) (D)
NS Package Number J24E



24-Lead Quad Cerpak (F)
NS Package Number W24B

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